

256 Kbit (32Kb x 8) UV EPROM and OTP EPROM

- 5V ± 10% SUPPLY VOLTAGE in READ OPERATION
- FAST ACCESS TIME: 45ns
- LOW POWER CONSUMPTION:
 - Active Current 30mA at 5MHz
 - Standby Current 100µA
- PROGRAMMING VOLTAGE: 12.75V ± 0.25V
- PROGRAMMING TIME: 100µs/byte (PRESTO II ALGORITHM)
- ELECTRONIC SIGNATURE
 - Manufacturer Code: 20h
 - Device Code: 8Dh

DESCRIPTION

The M27C256B is a 256 Kbit EPROM offered in the two ranges UV (ultra violet erase) and OTP (one time programmable). It is ideally suited for micro-processor systems and is organized as 32,768 by 8 bits.

The FDIP28W (window ceramic frit-seal package) has a transparent lid which allows the user to expose the chip to ultraviolet light to erase the bit pattern. A new pattern can then be written to the device by following the programming procedure.

For applications where the content is programmed only one time and erasure is not required, the M27C256B is offered in PDIP32, PLCC32 and TSOP28 (8 x 13.4 mm) packages.

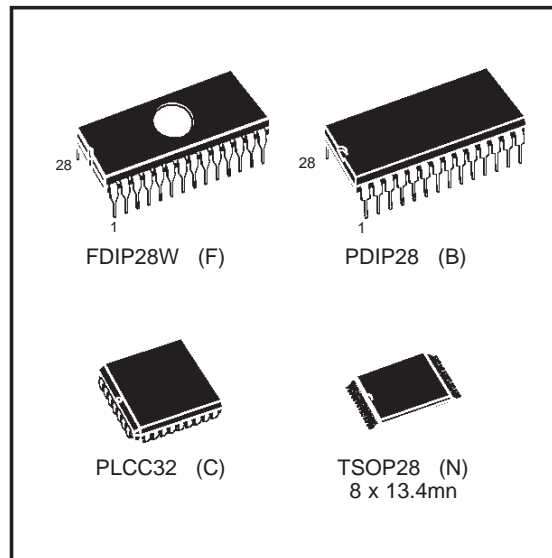


Figure 1. Logic Diagram

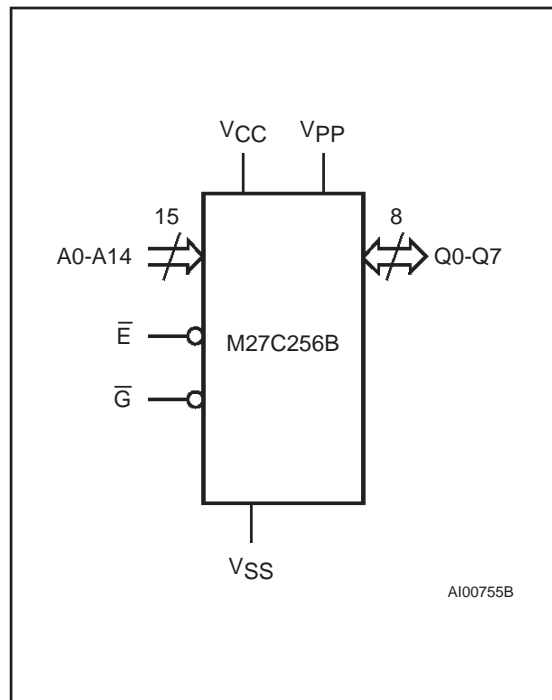
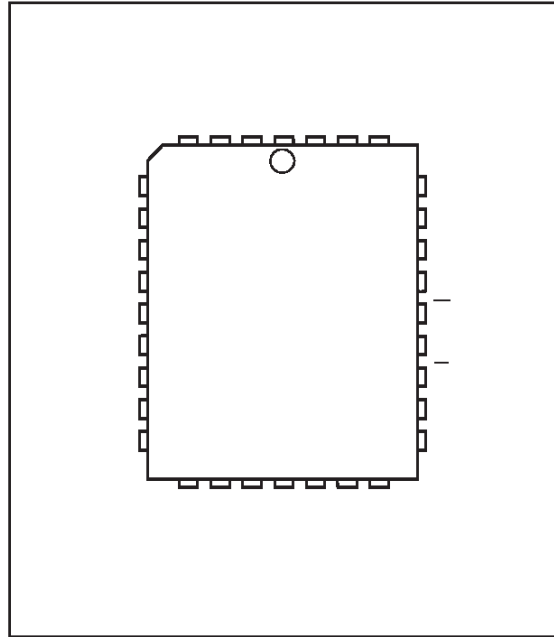
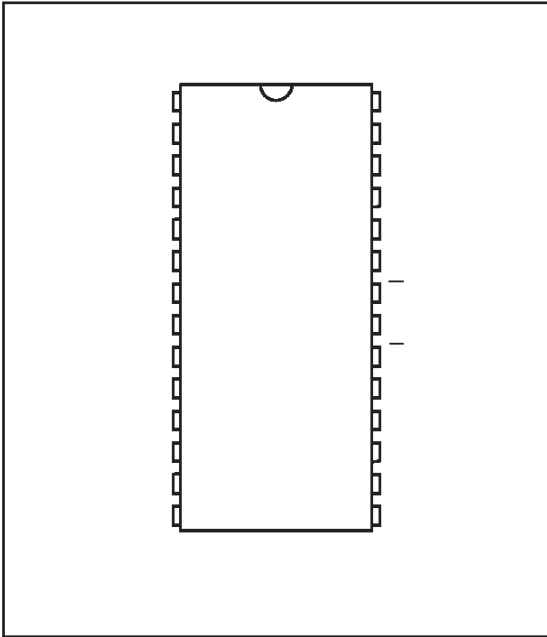
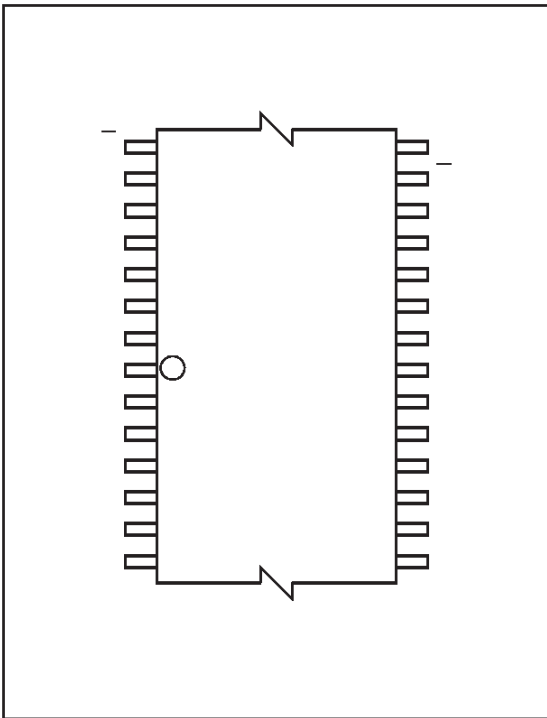


Table 1. Signal Names

A0-A14	Address Inputs
Q0-Q7	Data Outputs
\bar{E}	Chip Enable
\bar{G}	Output Enable
V _{PP}	Program Supply
V _{CC}	Supply Voltage
V _{SS}	Ground



Warning: NC = Not Connected, DU = Don't Use.



DEVICE OPERATION

The operating modes of the M27C256B are listed in the Operating Modes. A single power supply is required in the read mode. All inputs are TTL levels

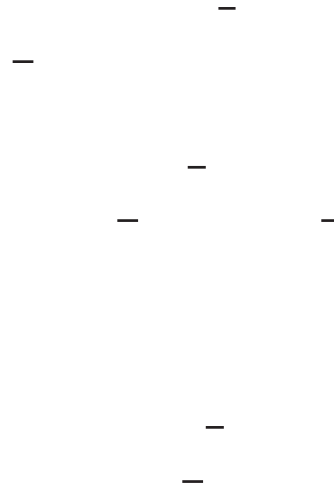


Table 2. Absolute Maximum Ratings ⁽¹⁾

Symbol	Parameter	Value	Unit
T _A	Ambient Operating Temperature ⁽³⁾	-40 to 125	°C
T _{BIAS}	Temperature Under Bias	-50 to 125	°C
T _{STG}	Storage Temperature	-65 to 150	°C
V _{IO} ⁽²⁾	Input or Output Voltages (except A9)	-2 to 7	V
V _{CC}	Supply Voltage	-2 to 7	V
V _{A9} ⁽²⁾	A9 Voltage	-2 to 13.5	V
V _{PP}	Program Supply Voltage	-2 to 14	V

Notes: 1. Except for the rating "Operating Temperature Range", stresses above those listed in the Table "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronics SURE Program and other relevant quality documents.

2. Minimum DC voltage on Input or Output is -0.5V with possible undershoot to -2.0V for a period less than 20ns. Maximum DC voltage on Output is V_{CC} +0.5V with possible overshoot to V_{CC} +2V for a period less than 20ns.

3. Depends on range.

Table 3. Operating Modes

Mode	\bar{E}	\bar{G}	A9	V _{PP}	Q0 - Q7
Read	V _{IL}	V _{IL}	X	V _{CC}	Data Out
Output Disable	V _{IL}	V _{IH}	X	V _{CC}	Hi-Z
Program	V _{IL} Pulse	V _{IH}	X	V _{PP}	Data In
Verify	V _{IH}	V _{IL}	X	V _{PP}	Data Out
Program Inhibit	V _{IH}	V _{IH}	X	V _{PP}	Hi-Z
Standby	V _{IH}	X	X	V _{CC}	Hi-Z
Electronic Signature	V _{IL}	V _{IL}	V _{ID}	V _{CC}	Codes

Note: X = V_{IH} or V_{IL}, V_{ID} = 12V ± 0.5V

Table 4. Electronic Signature

Identifier	A0	Q7	Q6	Q5	Q4	Q3	Q2	Q1	Q0	Hex Data
Manufacturer's Code	V _{IL}	0	0	1	0	0	0	0	0	20h
Device Code	V _{IH}	1	0	0	0	1	1	0	1	8Dh

Two Line Output Control

Because EPROMs are usually used in larger memory arrays, this product features a 2 line control function which accommodates the use of multiple memory connection. The two line control function allows:

- the lowest possible memory power dissipation,
- complete assurance that output bus contention will not occur.

For the most efficient use of these two control lines, \bar{E} should be decoded and used as the primary device selecting function, while \bar{G} should be made a common connection to all devices in the array and connected to the READ line from the system control bus. This ensures that all deselected memory devices are in their low power standby mode and that the output pins are only active when data is desired from a particular memory device.

Table 5. AC Measurement Conditions

	High Speed	Standard
Input Rise and Fall Times	≤ 10ns	≤ 20ns
Input Pulse Voltages	0 to 3V	0.4V to 2.4V
Input and Output Timing Ref. Voltages	1.5V	0.8V and 2V

Figure 3. AC Testing Input Output Waveform

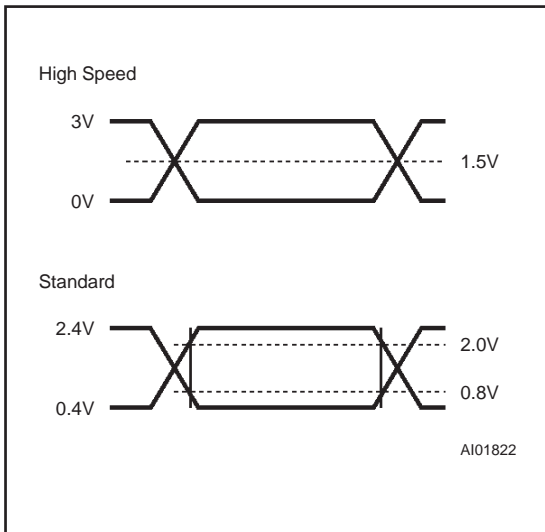


Figure 4. AC Testing Load Circuit

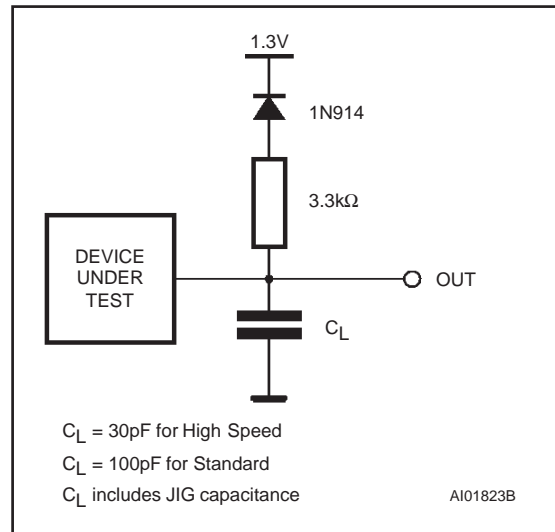


Table 6. Capacitance⁽¹⁾ (TA = 25 °C, f = 1 MHz)

Symbol	Parameter	Test Condition	Min	Max	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V		6	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0V		12	pF

Note: 1. Sampled only, not 100% tested.

System Considerations

The power switching characteristics of Advance CMOS EPROMs require careful decoupling of the devices. The supply current, I_{CC}, has three segments that are of interest to the system designer: the standby current level, the active current level, and transient current peaks that are produced by the falling and rising edges of \bar{E} . The magnitude of this transient current peaks is dependent on the capacitive and inductive loading of the device at the output.

The associated transient voltage peaks can be suppressed by complying with the two line output control and by properly selected decoupling capacitors. It is recommended that a 0.1μF ceramic capacitor be used on every device between V_{CC} and V_{SS}. This should be a high frequency capacitor of low inherent inductance and should be placed as close to the device as possible. In addition, a 4.7μF bulk electrolytic capacitor should be used between V_{CC} and V_{SS} for every eight devices. The bulk capacitor should be located near the power supply connection point. The purpose of the bulk capacitor is to overcome the voltage drop caused by the inductive effects of PCB traces.

Table 7. Read Mode DC Characteristics⁽¹⁾(T_A = 0 to 70°C, -40 to 85°C, -40 to 105°C or -40 to 125°C; V_{CC} = 5V ± 5% or 5V ± 10%; V_{PP} = V_{CC})

Symbol	Parameter	Test Condition	Min	Max	Unit
I _{LI}	Input Leakage Current	0V ≤ V _{IN} ≤ V _{CC}		±10	μA
I _{LO}	Output Leakage Current	0V ≤ V _{OUT} ≤ V _{CC}		±10	μA
I _{CC}	Supply Current	$\bar{E} = V_{IL}, \bar{G} = V_{IL},$ I _{OUT} = 0mA, f = 5MHz		30	mA
I _{CC1}	Supply Current (Standby) TTL	$\bar{E} = V_{IH}$		1	mA
I _{CC2}	Supply Current (Standby) CMOS	$\bar{E} > V_{CC} - 0.2V$		100	μA
I _{PP}	Program Current	V _{PP} = V _{CC}		100	μA
V _{IL}	Input Low Voltage		-0.3	0.8	V
V _{IH} ⁽²⁾	Input High Voltage		2	V _{CC} + 1	V
V _{OL}	Output Low Voltage	I _{OL} = 2.1mA		0.4	V
V _{OH}	Output High Voltage TTL	I _{OH} = -1mA	3.6		V
	Output High Voltage CMOS	I _{OH} = -100μA	V _{CC} - 0.7		V

Notes: 1. V_{CC} must be applied simultaneously with or before V_{PP} and removed simultaneously or after V_{PP}.
2. Maximum DC voltage on Output is V_{CC} +0.5V.

Table 8A. Read Mode AC Characteristics⁽¹⁾(T_A = 0 to 70°C, -40 to 85°C, -40 to 105°C or -40 to 125°C; V_{CC} = 5V ± 5% or 5V ± 10%; V_{PP} = V_{CC})

Symbol	Alt	Parameter	Test Condition	M27C256B								Unit
				-45 ⁽³⁾		-60		-70		-80		
				Min	Max	Min	Max	Min	Max	Min	Max	
t _{AVQV}	t _{ACC}	Address Valid to Output Valid	$\bar{E} = V_{IL}, \bar{G} = V_{IL}$		45		60		70		80	ns
t _{ELQV}	t _{CE}	Chip Enable Low to Output Valid	$\bar{G} = V_{IL}$		45		60		70		80	ns
t _{GLQV}	t _{OE}	Output Enable Low to Output Valid	$\bar{E} = V_{IL}$		25		30		35		40	ns
t _{EHQZ} ⁽²⁾	t _{DF}	Chip Enable High to Output Hi-Z	$\bar{G} = V_{IL}$	0	25	0	30	0	30	0	30	ns
t _{GHQZ} ⁽²⁾	t _{DF}	Output Enable High to Output Hi-Z	$\bar{E} = V_{IL}$	0	25	0	30	0	30	0	30	ns
t _{AXQX}	t _{OH}	Address Transition to Output Transition	$\bar{E} = V_{IL}, \bar{G} = V_{IL}$	0		0		0		0		ns

Notes: 1. V_{CC} must be applied simultaneously with or before V_{PP} and removed simultaneously or after V_{PP}.
2. Sampled only, not 100% tested.
3. In case of 45ns speed see High Speed AC measurement conditions.

M27C256B

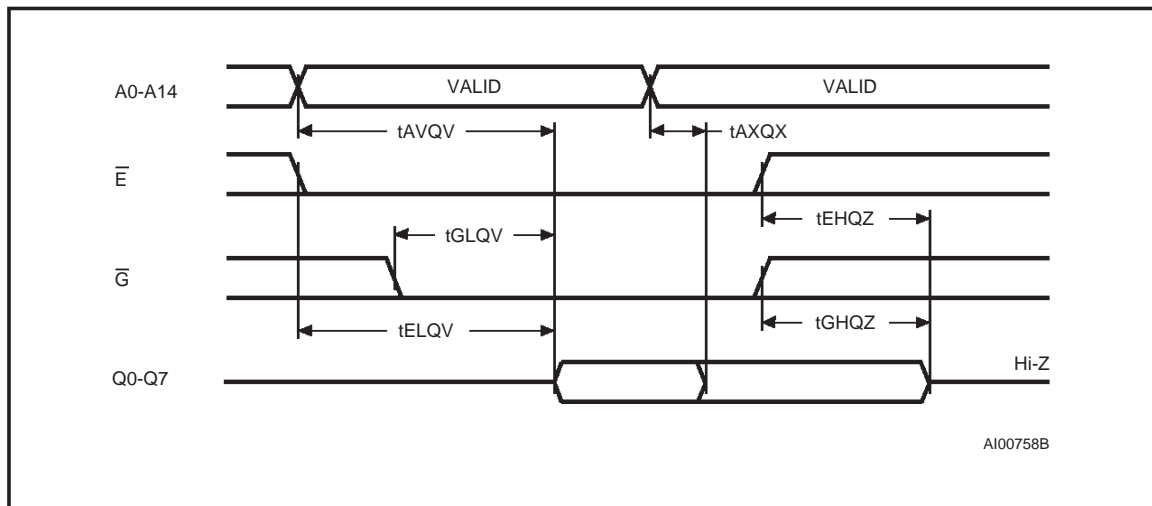
Table 8B. Read Mode AC Characteristics ⁽¹⁾

($T_A = 0$ to 70°C , -40 to 85°C , -40 to 105°C or -40 to 125°C ; $V_{CC} = 5V \pm 5\%$ or $5V \pm 10\%$; $V_{PP} = V_{CC}$)

Symbol	Alt	Parameter	Test Condition	M27C256B								Unit
				-90		-10		-12		-15/-20/-25		
				Min	Max	Min	Max	Min	Max	Min	Max	
t_{AVQV}	t_{ACC}	Address Valid to Output Valid	$\bar{E} = V_{IL}, \bar{G} = V_{IL}$		90		100		120		150	ns
t_{ELQV}	t_{CE}	Chip Enable Low to Output Valid	$\bar{G} = V_{IL}$		90		100		120		150	ns
t_{GLQV}	t_{OE}	Output Enable Low to Output Valid	$\bar{E} = V_{IL}$		40		50		60		65	ns
$t_{EHQZ}^{(2)}$	t_{DF}	Chip Enable High to Output Hi-Z	$\bar{G} = V_{IL}$	0	30	0	30	0	40	0	50	ns
$t_{GHQZ}^{(2)}$	t_{DF}	Output Enable High to Output Hi-Z	$\bar{E} = V_{IL}$	0	30	0	30	0	40	0	50	ns
t_{AXQX}	t_{OH}	Address Transition to Output Transition	$\bar{E} = V_{IL}, \bar{G} = V_{IL}$	0		0		0		0		ns

Notes: 1. V_{CC} must be applied simultaneously with or before V_{PP} and removed simultaneously or after V_{PP} .
2. Sampled only, not 100% tested.

Figure 5. Read Mode AC Waveforms



Programming

When delivered (and after each erasure for UV EPROM), all bits of the M27C256B are in the "1" state. Data is introduced by selectively programming "0"s into the desired bit locations. Although only "0"s will be programmed, both "1"s and "0"s can be present in the data word. The only way to

change a '0' to a '1' is by die exposition to ultraviolet light (UV EPROM). The M27C256B is in the programming mode when V_{PP} input is at $12.75V$, \bar{G} is at V_{IH} and \bar{E} is pulsed to V_{IL} . The data to be programmed is applied to 8 bits in parallel to the data output pins. The levels required for the address and data inputs are TTL. V_{CC} is specified to be $6.25V \pm 0.25V$.

Table 9. Programming Mode DC Characteristics ⁽¹⁾
 (T_A = 25 °C; V_{CC} = 6.25V ± 0.25V; V_{PP} = 12.75V ± 0.25V)

Symbol	Parameter	Test Condition	Min	Max	Unit
I _{LI}	Input Leakage Current	V _{IL} ≤ V _{IN} ≤ V _{IH}		±10	μA
I _{CC}	Supply Current			50	mA
I _{PP}	Program Current	$\bar{E} = V_{IL}$		50	mA
V _{IL}	Input Low Voltage		-0.3	0.8	V
V _{IH}	Input High Voltage		2	V _{CC} + 0.5	V
V _{OL}	Output Low Voltage	I _{OL} = 2.1mA		0.4	V
V _{OH}	Output High Voltage TTL	I _{OH} = -1mA	3.6		V
V _{ID}	A9 Voltage		11.5	12.5	V

Note: 1. V_{CC} must be applied simultaneously with or before V_{PP} and removed simultaneously or after V_{PP}.

Table 10. Programming Mode AC Characteristics ⁽¹⁾
 (T_A = 25 °C; V_{CC} = 6.25V ± 0.25V; V_{PP} = 12.75V ± 0.25V)

Symbol	Alt	Parameter	Test Condition	Min	Max	Unit
t _{AVEL}	t _{AS}	Address Valid to Chip Enable Low		2		μs
t _{QVEL}	t _{DS}	Input Valid to Chip Enable Low		2		μs
t _{VPHEL}	t _{VPS}	V _{PP} High to Chip Enable Low		2		μs
t _{VCHL}	t _{VCS}	V _{CC} High to Chip Enable Low		2		μs
t _{ELEH}	t _{PW}	Chip Enable Program Pulse Width		95	105	μs
t _{EHQX}	t _{DH}	Chip Enable High to Input Transition		2		μs
t _{QXGL}	t _{OES}	Input Transition to Output Enable Low		2		μs
t _{GLQV}	t _{OE}	Output Enable Low to Output Valid			100	ns
t _{GHQZ}	t _{DFP}	Output Enable High to Output Hi-Z		0	130	ns
t _{GHAX}	t _{AH}	Output Enable High to Address Transition		0		ns

Note: 1. V_{CC} must be applied simultaneously with or before V_{PP} and removed simultaneously or after V_{PP}.

Figure 6. Programming and Verify Modes AC Waveforms

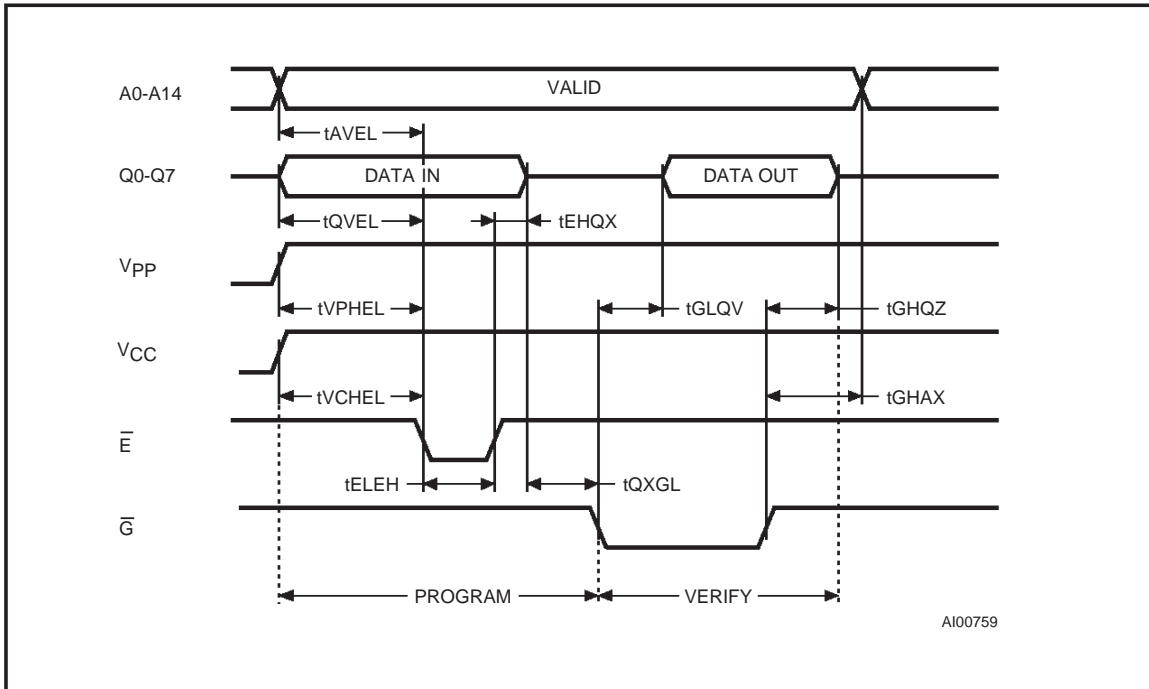
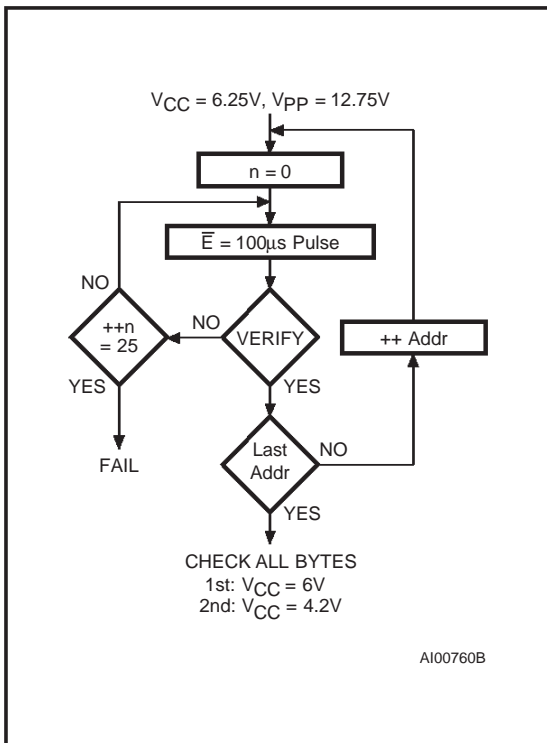


Figure 7. Programming Flowchart



PRESTO II Programming Algorithm

PRESTO II Programming Algorithm allows to program the whole array with a guaranteed margin, in a typical time of 3.5 seconds. Programming with PRESTO II involves the application of a sequence of 100µs program pulses to each byte until a correct verify occurs (see Figure 7). During programming and verify operation, a MARGIN MODE circuit is automatically activated in order to guarantee that each cell is programmed with enough margin. No overprogram pulse is applied since the verify in MARGIN MODE provides necessary margin to each programmed cell.

Program Inhibit

Programming of multiple M27C256Bs in parallel with different data is also easily accomplished. Except for \bar{E} , all like inputs including \bar{G} of the parallel M27C256B may be common. A TTL low level pulse applied to a M27C256B's \bar{E} input, with V_{PP} at 12.75 V, will program that M27C256B. A high level \bar{E} input inhibits the other M27C256Bs from being programmed.

Program Verify

A verify (read) should be performed on the programmed bits to determine that they were correctly programmed. The verify is accomplished with \bar{G} at V_{IL} , \bar{E} at V_{IH} , V_{PP} at 12.75V and V_{CC} at 6.25V.

On-Board Programming

The M27C256B can be directly programmed in the application circuit. See the relevant Application Note AN620.

Electronic Signature

The Electronic Signature (ES) mode allows the reading out of a binary code from an EPROM that will identify its manufacturer and type. This mode is intended for use by programming equipment to automatically match the device to be programmed with its corresponding programming algorithm. The ES mode is functional in the $25^{\circ}\text{C} \pm 5^{\circ}\text{C}$ ambient temperature range that is required when programming the M27C256B. To activate the ES mode, the programming equipment must force 11.5V to 12.5V on address line A9 of the M27C256B, with $V_{CC} = V_{PP} = 5\text{V}$. Two identifier bytes may then be sequenced from the device outputs by toggling address line A0 from V_{IL} to V_{IH} . All other address lines must be held at V_{IL} during Electronic Signature mode. Byte 0 ($A0=V_{IL}$) represents the manufacturer code and byte 1 ($A0=V_{IH}$) the device identifier code. For the STMicroelectronics M27C256B, these two identifier bytes are given in Table 4 and can be read-out on outputs Q0 to Q7.

ERASURE OPERATION (applies for UV EPROM)

The erasure characteristics of the M27C256B is such that erasure begins when the cells are exposed to light with wavelengths shorter than approximately 4000 Å. It should be noted that sunlight and some type of fluorescent lamps have wavelengths in the 3000-4000 Å range. Research shows that constant exposure to room level fluorescent lighting could erase a typical M27C256B in about 3 years, while it would take approximately 1 week to cause erasure when exposed to direct sunlight. If the M27C256B is to be exposed to these types of lighting conditions for extended periods of time, it is suggested that opaque labels be put over the M27C256B window to prevent unintentional erasure. The recommended erasure procedure for the M27C256B is exposure to short wave ultraviolet light which has wavelength 2537 Å. The integrated dose (i.e. UV intensity x exposure time) for erasure should be a minimum of 15 W-sec/cm². The erasure time with this dosage is approximately 15 to 20 minutes using an ultraviolet lamp with 12000 μW/cm² power rating. The M27C256B should be placed within 2.5 cm (1 inch) of the lamp tubes during the erasure. Some lamps have a filter on their tubes which should be removed before erasure.

M27C256B

ORDERING INFORMATION SCHEME

Example: M27C256B -70 X C 1 TR

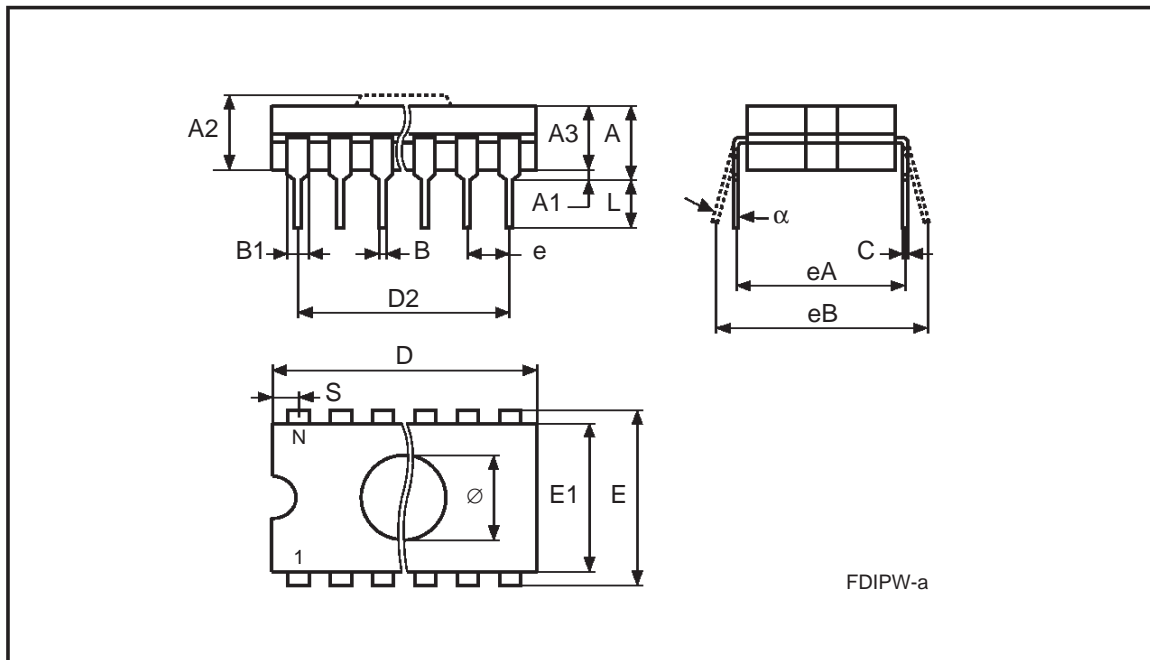
Speed		V _{CC} Tolerance		Package		Temperature Range		Option	
-45 ⁽¹⁾	45 ns	X	± 5%	F	FDIP28W	1	0 to 70 °C	X	Additional Burn-in
-60	60 ns	blank	± 10%	B	PDIP28	6	-40 to 85 °C		
-70	70 ns			C	PLCC32	7	-40 to 105 °C	TR	Tape & Reel Packing
-80	80 ns			N	TSOP28 8 x 13.4mm	3	-40 to 125 °C		
-90	90 ns								
-10	100 ns								
-12	120 ns								
-15	150 ns								
-20	200 ns								
-25	250 ns								

Note: 1. High Speed, see AC Characteristics section for further information.

For a list of available options (Speed, Package, etc...) or for further information on any aspect of this device, please contact the STMicroelectronics Sales Office nearest to you.

FDIP28W - 28 pin Ceramic Frit-seal DIP, with window

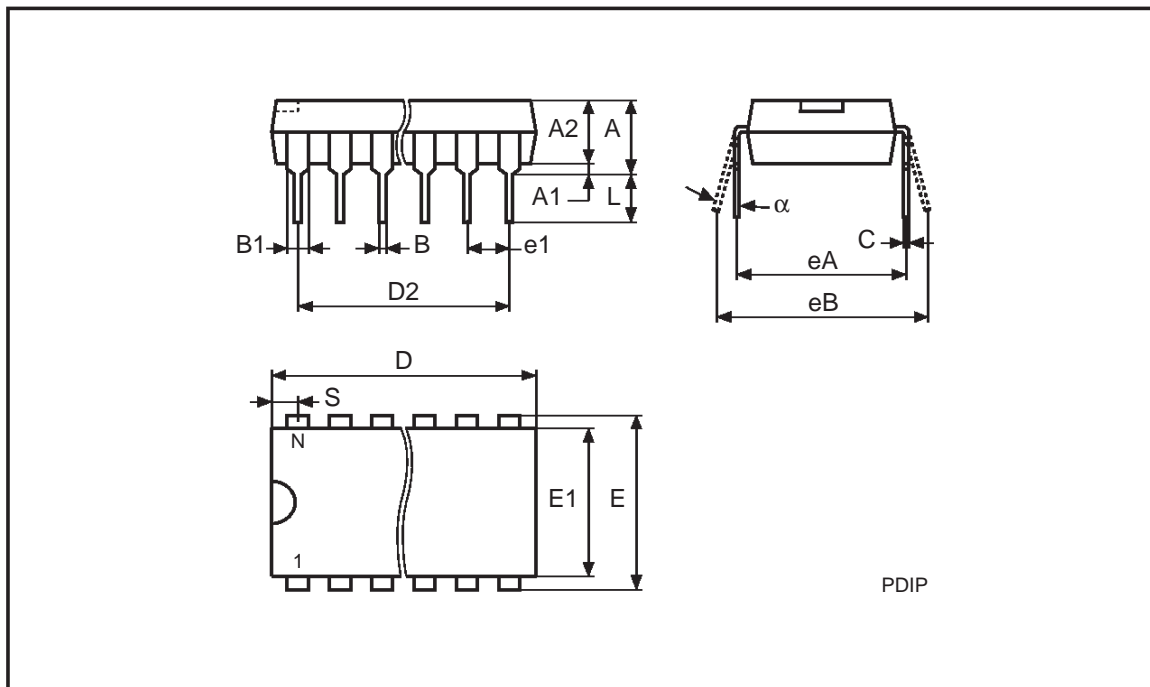
Symb	mm			inches		
	Typ	Min	Max	Typ	Min	Max
A			5.71			0.225
A1		0.50	1.78		0.020	0.070
A2		3.90	5.08		0.154	0.200
B		0.40	0.55		0.016	0.022
B1		1.17	1.42		0.046	0.056
C		0.22	0.31		0.009	0.012
D			38.10			1.500
E		15.40	15.80		0.606	0.622
E1		13.05	13.36		0.514	0.526
e1	2.54	–	–	0.100	–	–
e3	33.02	–	–	1.300	–	–
eA		16.17	18.32		0.637	0.721
L		3.18	4.10		0.125	0.161
S		1.52	2.49		0.060	0.098
∅	7.11	–	–	0.280	–	–
α		4°	15°		4°	15°
N		28			28	



Drawing is not to scale.

PDIP28 - 28 pin Plastic DIP, 600 mils width

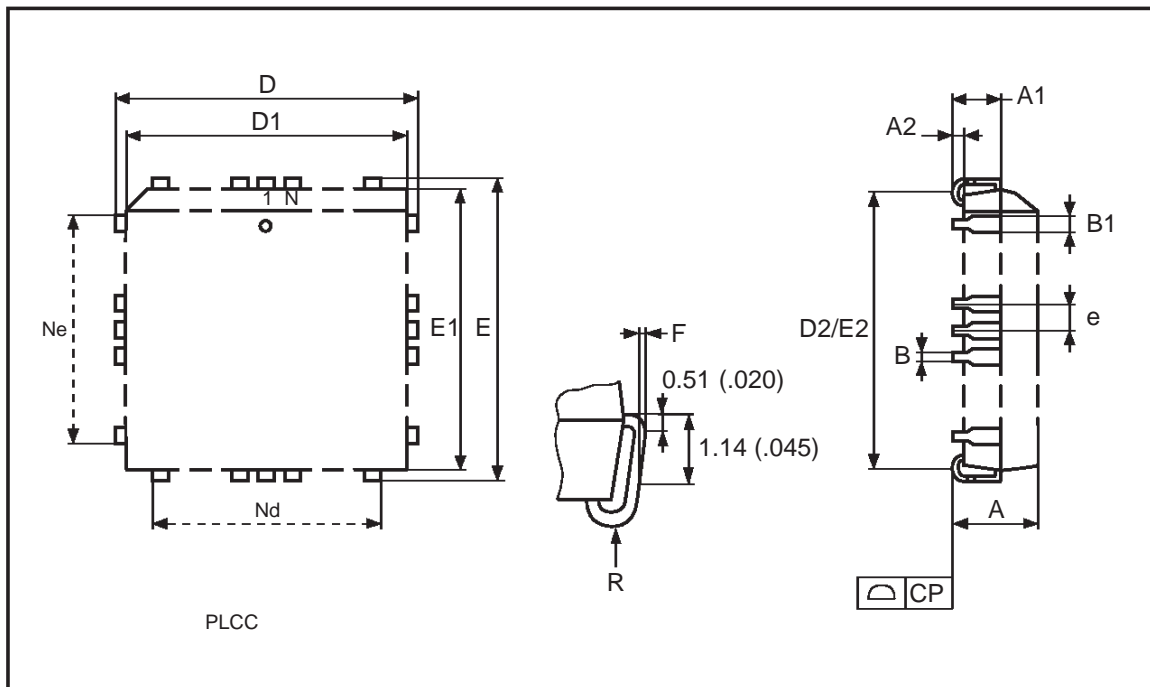
Symb	mm			inches		
	Typ	Min	Max	Typ	Min	Max
A		–	5.08		–	0.200
A1		0.38	–		0.015	–
A2		3.56	4.06		0.140	0.160
B		0.38	0.51		0.015	0.020
B1	1.52	–	–	0.060	–	–
C		0.20	0.30		0.008	0.012
D		36.83	37.34		1.450	1.470
D2	33.02	–	–	1.300	–	–
E	15.24	–	–	0.600	–	–
E1		13.59	13.84		0.535	0.545
e1	2.54	–	–	0.100	–	–
eA	14.99	–	–	0.590	–	–
eB		15.24	17.78		0.600	0.700
L		3.18	3.43		0.125	0.135
S		1.78	2.08		0.070	0.082
α		0°	10°		0°	10°
N		28			28	



Drawing is not to scale.

PLCC32 - 32 lead Plastic Leaded Chip Carrier - rectangular

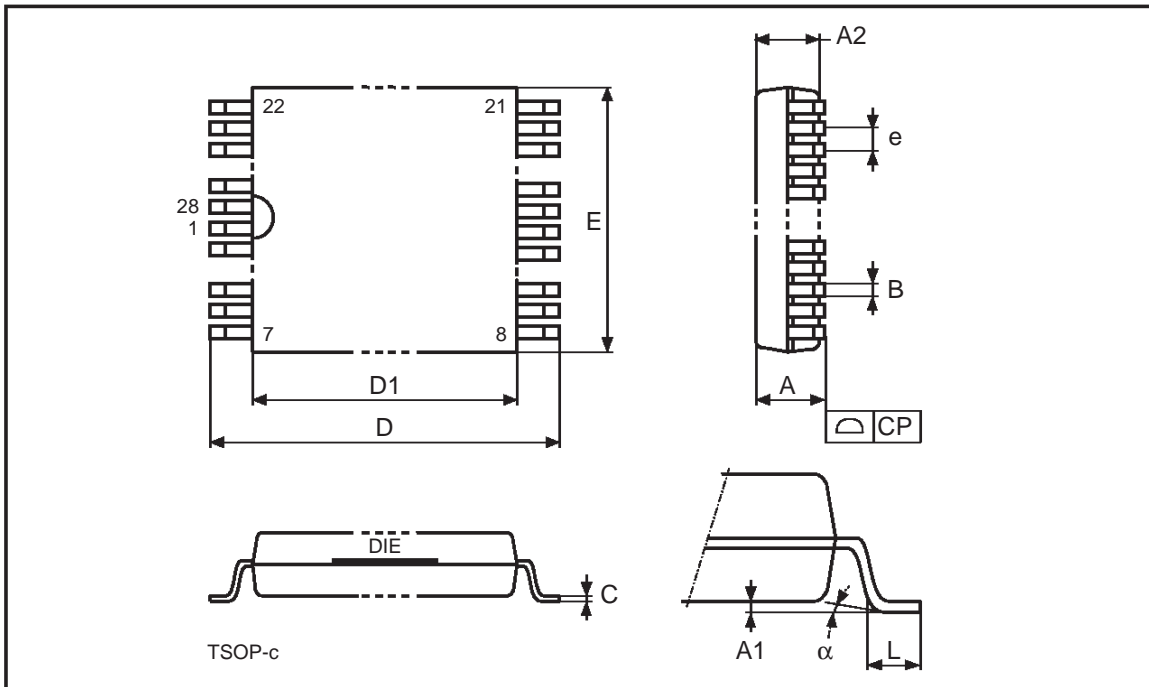
Symb	mm			inches		
	Typ	Min	Max	Typ	Min	Max
A		2.54	3.56		0.100	0.140
A1		1.52	2.41		0.060	0.095
A2		–	0.38		–	0.015
B		0.33	0.53		0.013	0.021
B1		0.66	0.81		0.026	0.032
D		12.32	12.57		0.485	0.495
D1		11.35	11.56		0.447	0.455
D2		9.91	10.92		0.390	0.430
E		14.86	15.11		0.585	0.595
E1		13.89	14.10		0.547	0.555
E2		12.45	13.46		0.490	0.530
e	1.27	–	–	0.050	–	–
F		0.00	0.25		0.000	0.010
R	0.89	–	–	0.035	–	–
N		32			32	
Nd		7			7	
Ne		9			9	
CP			0.10			0.004



Drawing is not to scale.

TSOP28 - 28 lead Plastic Thin Small Outline, 8 x 13.4mm

Symb	mm			inches		
	Typ	Min	Max	Typ	Min	Max
A		1.00	1.25		0.039	0.049
A1			0.20			0.008
A2		0.95	1.05		0.037	0.041
B			0.30			0.012
C		0.10	0.21		0.004	0.008
D		13.10	13.70		0.516	0.539
D1		11.70	11.90		0.461	0.469
E		7.90	8.25		0.311	0.325
e	0.55	-	-	0.022	-	-
L		0.30	0.70		0.012	0.028
α		0°	5°		0°	5°
N	28			28		
CP			0.10			0.004



Drawing is not to scale.

Information furnished is believed to be accurate and reliable. However, STMicroelectronics assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of STMicroelectronics. Specifications mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. STMicroelectronics products are not authorized for use as critical components in life support devices or systems without express written approval of STMicroelectronics.

The ST logo is a registered trademark of STMicroelectronics

© 1998 STMicroelectronics - All Rights Reserved

STMicroelectronics GROUP OF COMPANIES

Australia - Brazil - China - France - Germany - Italy - Japan - Korea - Malaysia - Malta - Mexico - Morocco - The Netherlands - Singapore - Spain - Sweden - Switzerland - Taiwan - Thailand - United Kingdom - U.S.A.

